

<b>Notice of References Cited</b>	Application/Control No. 10/590,637		Applicant(s)/Patent Under Reexamination ZHANG, CAITENG	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,424,346 A	01-1984	Hall et al.	536/20
*	B	US-4,617,244 A	10-1986	Greene, Roland M.	429/203
*	C	US-4,921,949 A	05-1990	Lang et al.	536/20
*	D	US-5,059,654 A	10-1991	Hou et al.	525/54.1
*	E	US-5,599,916 A	02-1997	Dutkiewicz et al.	536/20
*	F	US-5,912,000 A	06-1999	Podolski et al.	424/278.1
*	G	US-2001/0014334 A1	08-2001	SEID et al.	424/193.1
*	H	US-2002/0031561 A1	03-2002	Diaz et al.	424/750
*	I	US-2002/0143172 A1	10-2002	Ookawa et al.	536/56
*	J	US-2003/0054949 A1	03-2003	Chang et al.	502/159
*	K	US-2003/0055003 A1	03-2003	Bar-Or et al.	514/18
*	L	US-6,589,942 B1	07-2003	Ben-Shalom et al.	514/55
*	M	US-6,627,099 B2	09-2003	Ono et al.	252/62.2

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	KR2001-0106359A	11-2001	Korea	Cho	
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Machine translation of KR 2001-0106359			
	V				
	W				
	X				

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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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Liam J. Heincer

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1796

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0224974 A1	12-2003	Bolotin, Elijah M.	514/6
*	B	US-2004/0215045 A1	10-2004	Herrera et al.	585/818
*	C	US-2005/0115890 A1	06-2005	Demmer et al.	210/502.1
*	D	US-2005/0182021 A1	08-2005	Nichols et al.	514/054
*	E	US-2005/0227290 A1	10-2005	Lippard et al.	435/007.1
*	F	US-2006/0151396 A1	07-2006	Ren et al.	210/684
*	G	US-7,365,190 B2	04-2008	Couture et al.	536/123.1
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

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	V	
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